



Power MOSFETS

DATASHEET

LM30500PAI3A

P-Channel
Enhancement Mode MOSFET

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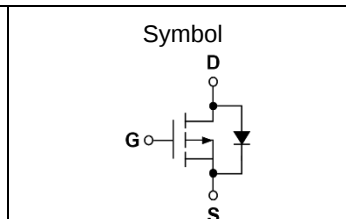
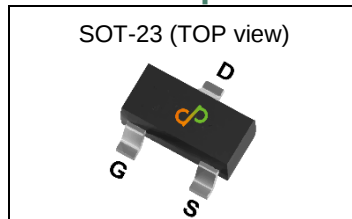


Quality Management Systems

ISO 9001:2015 Certificate

P-Channel Enhancement Mode MOSFET

Pin Description



Ordering Information

Symbol	P-Channel	Unit
V_{DSS}	-30	V
$R_{DS(ON)-Max}$	50	mΩ
I_D	-3.8	A

Feature

- Fast switching speed
- Reliable and Rugged
- ROHS Compliant & Halogen-Free

Applications

- Portable Equipment
- Battery Powered System

Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM30500PAI3A	SOT-23	Tape & Reel	3000 / Tape & Reel	02□□□

Note : □□□ = Lot Code

Absolute Maximum Ratings (T_J=25°C Unless Otherwise Noted)

Symbol	Parameter		P-Channel	Unit
V_{DSS}	Drain-Source Voltage		-30	V
V_{GSS}	Gate-Source Voltage		±20	
T_J	Maximum Junction Temperature		150	°C
T_{STG}	Storage Temperature Range		-55 to 150	°C
$I_{DM}^{①}$	Pulse Drain Current Tested	$T_A=25^{\circ}C$	-9.5	A
I_D	Continuous Drain Current	$T_A=25^{\circ}C$	-3.8	A
		$T_A=70^{\circ}C$	-3	
P_D	Maximum Power Dissipation	$T_A=25^{\circ}C$	1.1	W
		$T_A=70^{\circ}C$	0.7	
$I_{AS}^{②}$	Avalanche Current, Single pulse	L=0.1mH	-12.5	A
$E_{AS}^{②}$	Avalanche Energy, Single pulse	L=0.1mH	7.8	mJ

Thermal Characteristics

Symbol	Parameter		Rating	Unit
$R_{\theta JA}^{③}$	Thermal Resistance-Junction to Ambient	Steady State	110	°C/W

Note ① : Max. current is limited by junction temperature.

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150°C

Note ③ : Surface Mounted on 1in² FR-4 board with 1oz.

P-Channel Electrical Characteristics ($T_J=25^{\circ}\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Electrical Characteristics						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _{DS} =-250uA	-30	-	-	V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =-24V, V _{GS} =0V	-	-	-1	uA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _{DS} =-250uA	-1	-1.5	-2	V
I _{GSS}	Gate Leakage Current	V _{GS} =±20V, V _{DS} =0V	-	-	±100	nA
R _{DS(ON)} ④	Drain-Source On-state Resistance	V _{GS} =-10V, I _{DS} =-4.5A	-	40	50	mΩ
		V _{GS} =-4.5V, I _{DS} =-3.5A	-	60	70	
gfs	Forward Transconductance	V _{DS} =-10V, I _{DS} =-4.5A	-	1.7	-	S
Dynamic Characteristics ⑥						
R _G	Gate Resistance	V _{GS} =0V, V _{DS} =0V, Freq.=1MHz	-	18.5	-	Ω
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =-15V, Freq.=1MHz	-	577	-	pF
C _{oss}	Output Capacitance		-	65	-	
C _{rss}	Reverse Transfer Capacitance		-	56	-	
td(ON)	Turn-on Delay Time	V _{GS} =-10V, V _{DS} =-15V, Id=-1A, RGEN=6Ω	-	8	-	nS
tr	Turn-on Rise Time		-	10	-	
td(OFF)	Turn-off Delay Time		-	18	-	
tf	Turn-off Fall Time		-	8	-	
Qg	Total Gate Charge	V _{GS} =-4.5V, V _{DS} =-15V Id=-4A	-	4.6	-	nC
Qg	Total Gate Charge	V _{GS} =-10V, V _{DS} =-15V, Id=-4A	-	9.5	-	
Qgs	Gate-Source Charge		-	1.7	-	
Qgd	Gate-Drain Charge		-	2	-	
Source-Drain Characteristics						
VSD④	Diode Forward Voltage	ISD=-1A, VGS=0V	-	-0.75	-1.1	V
ttr	Reverse Recovery Time	IF=-4A, VR=-15V	-	16	-	nS
Qrr	Reverse Recovery Charge	dIF/dt=100A/μs	-	10	-	nC

Note ④ : Pulse test (pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$).

Note ⑤ : Guaranteed by design, not subject to production testing.

P-Channel Typical Characteristics

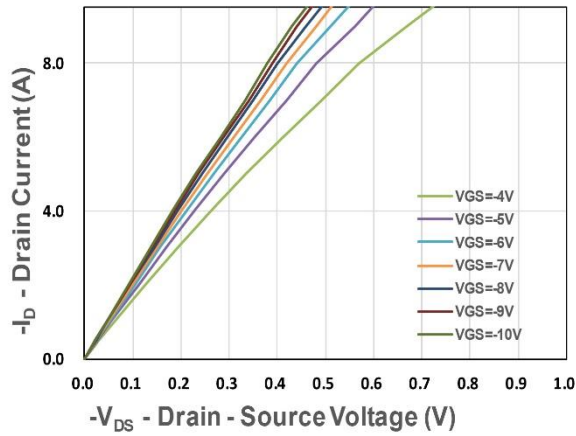


Figure 1. Output Characteristics

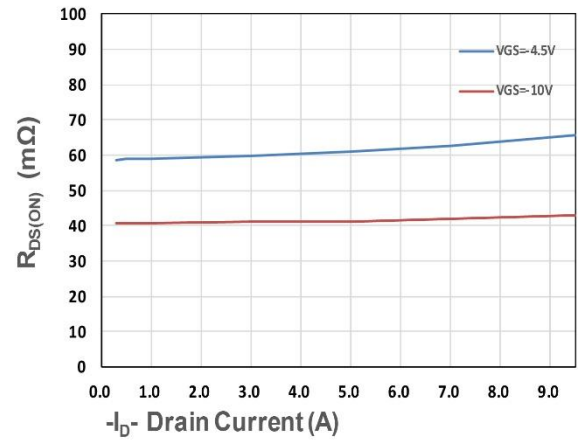


Figure 2. On-Resistance vs. ID

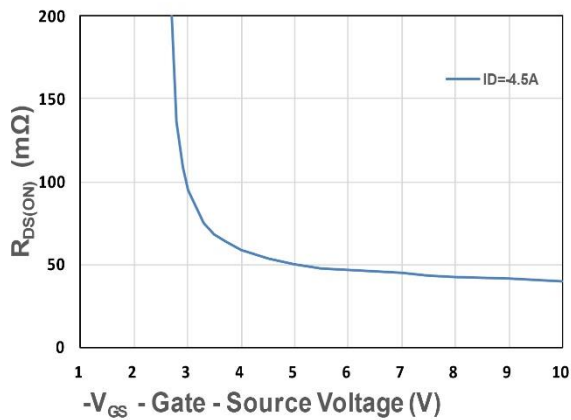


Figure 3. On-Resistance vs. VGS

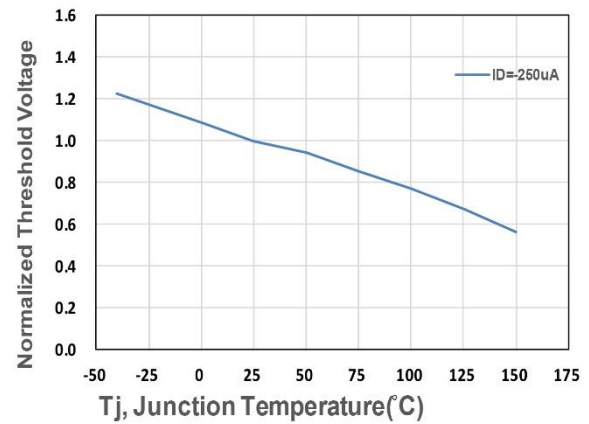


Figure 4. Gate Threshold Voltage

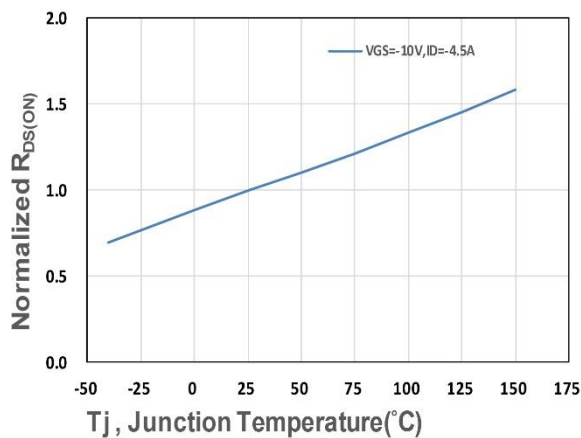


Figure 5. Drain-Source On Resistance

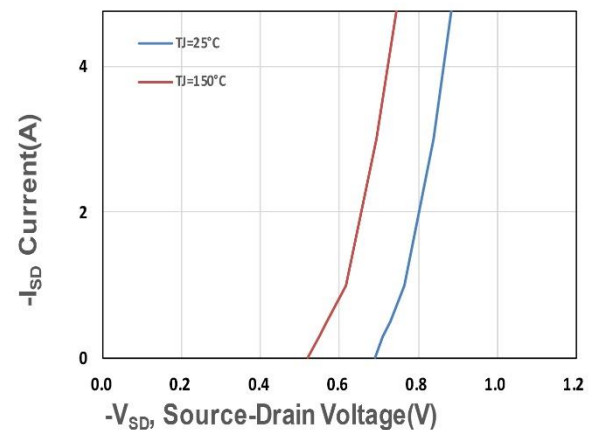


Figure 6. Source-Drain Diode Forward

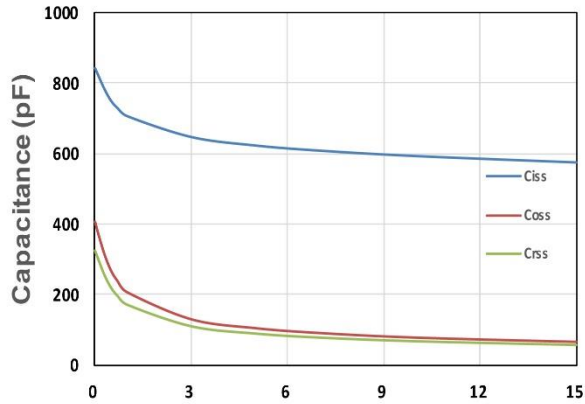


Figure 7. Capacitance

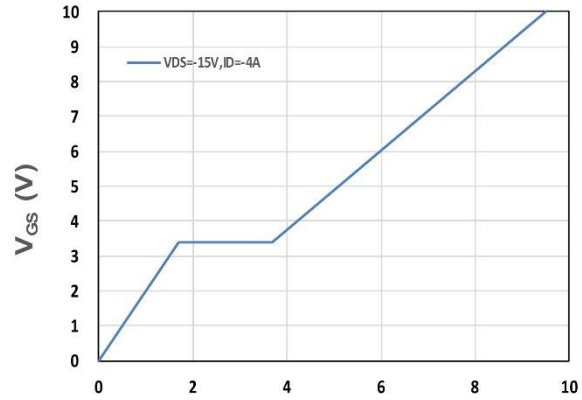


Figure 8. Gate Charge Characteristics

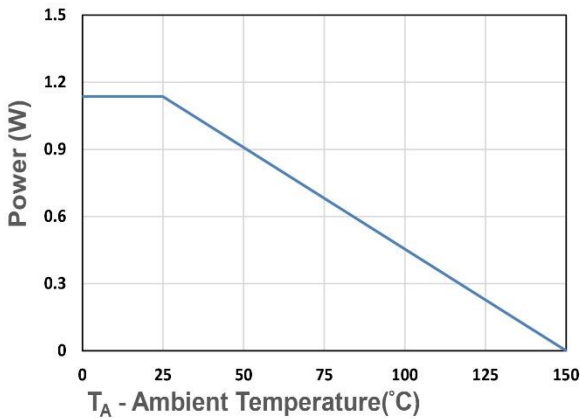


Figure 9. Power Dissipation

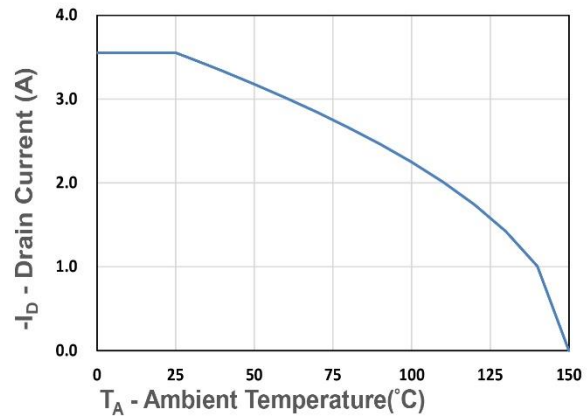


Figure 10. Drain Current

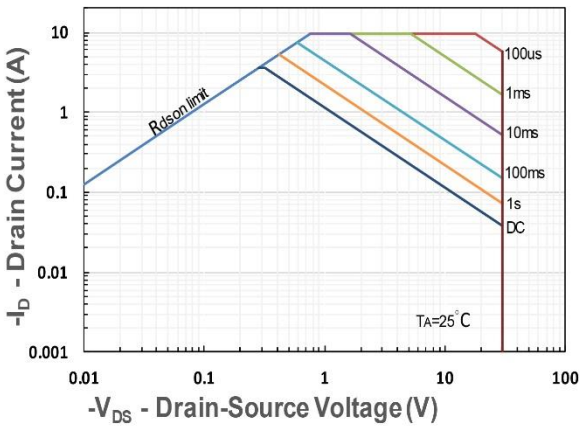


Figure 11. Safe Operating Area

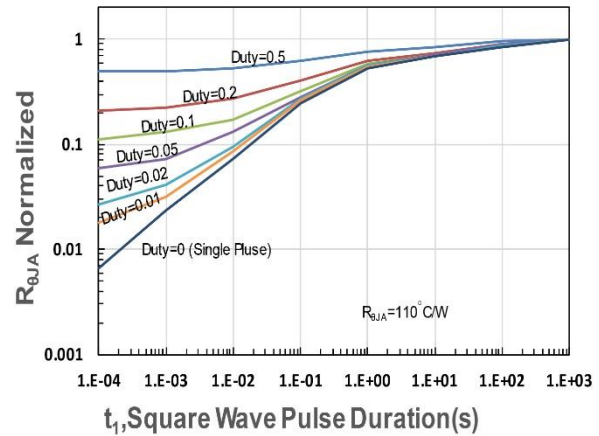


Figure 12. $R_{\theta JA}$ Transient Thermal Impedance